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ARTICLE TYPE

Synthesis of BiVO₄ Nanoflake Array Films for Photoelectrochemical Water Oxidation

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Because of the potential for application in photoelectrochemical cells for water splitting, synthesis of nanostructured BiVO₄ is receiving increasing attention. Here we report a simple new drop-casting method for the first time to synthesize un-doped and doped bismuth vanadate (BiVO₄) nanoflake array films. Synthesis parameters such as the amount of polyethylene glycol 600 (PEG-600) and the ¹⁰ precursor solution drying time are investigated to optimize the films for photoelectrochemical water oxidation. The BiVO₄ films consisting of nanoflakes with an average thickness of 20 nm and length of 2 μ m were synthesized from a precursor solution containing Bi³⁺, V³⁺ and PEG-600 with a Bi: V: PEG-600 volume ratio of 2: 2: 1, dried at 135°C for 55 min. Photoelectrochemical measurements show that the BiVO₄ nanoflake array films have higher photoelectrochemical activity than the BiVO₄ nanoparticle films. Additionally, the nanoflake array films demonstrate the best photoelectrochemical activity with photocurrent densities about 2 times higher than the un-doped BiVO₄ nanoflake films and greater than the photocurrents of individually Mo doped or W doped BiVO₄ films. The origin of enhanced photoelectrochemical activity through the BiVO₄ or slightly enhanced water oxidation kinetics.

1. Introduction

²⁰ Synthesis of semiconductor nanostructure array films has attracted considerable attention over the past decade, both because of their unique electronic and optical properties, and potential application in photovoltaic or photoelectrochemical devices, such as dye-sensitized solar cells and solar water ²⁵ splitting cells.¹⁻⁷ In comparison to bulk semiconductor materials, nanostructure array films can offer direct pathways for carrier transport as well as a large semiconductor-electrolyte interface,³. ^{8, 9} which may improve the performance of photoelectrochemical devices such as photoanodes for water oxidation. In recent years,
³⁰ many photoanodes have been synthesized in nanostructured geometries, such as nanotube,^{7, 10} nanorod ^{11, 12} and nanowire ¹³ arrays. In many instances these nanostructured arrays have shown enhanced efficiency for photoelectrochemical water oxidation.

Monoclinic bismuth vanadate (BiVO₄) has been considered a ³⁵ promising material for photoelectrochemical water oxidation due to its moderate bandgap (~2.4 eV) and appropriate band edge

positions,^{14, 15} allowing it to absorb as much as 11% of the solar spectrum to drive the water splitting reactions. Assuming a quantum yield of 100% in BiVO₄, photocurrents of ~7.5 mA/cm² could be achieved under AM1.5 G illumination.¹⁶ However, the 5 best performing films developed to date fall well short of this value. The major limiting factors identified include low mobility of carriers, slow water oxidation kinetics, and high electron-hole recombination rates compared to other semiconductors of interest such as TiO₂ and WO₃.¹⁷⁻²⁰ To address these issues, several 10 strategies have been developed to improve the photoelectrochemical activity of BiVO₄, such as doping with foreign elements (Mo, W),²¹⁻²⁴ hydrogen reduction to create oxygen vacancies,²⁵ coupling with co-catalysts (FeOOH, Co-Pi)^{17,} ^{18, 26, 27} or other semiconductors to form stable heterojunction 15 photoanodes.^{28, 29} Another strategy is synthesizing BiVO₄ as nanostructured films, in which the photogenerated holes can traverse a shorter distance to be collected at the electrode/solution interface, and thus the holes have a lower chance of recombining with the electrons before participating in electrochemical 20 reactions. Nevertheless, there are only a few reports that describe synthesis of BiVO₄ nanostructure array films up to now.⁵ and the reported synthetic method relies on relatively complicated procedures and conditions, which implies high cost and lowsuitability for implementation on a large scale. We were inspired 25 by work using structure-directing agents with other metal oxides such as ZnO ³⁰ and WO₃^{31, 32}, to synthesize nanostructured films of BiVO₄ using low-cost and scalable techniques.

Herein, we report a new, simple, and cost-effective dropcasting method for synthesizing BiVO₄ and Mo and W doped ³⁰ BiVO₄ nanoflake array films on fluorine-doped tin oxide (FTO) coated glass substrates. This synthesis technique allows for easy control of both the morphology and chemical composition to improve the photoelectrochemical activity of BiVO₄ films. Films ranging in morphology from nanoflake arrays to agglomerated ³⁵ nanoparticles were tested to evaluate their performance as photoanodes. The BiVO₄ nanoflake array films showed better photoelectrochemical activity than BiVO₄ nanoparticle films. Furthermore, incorporation of 2% W and 6% Mo into the BiVO₄ nanoflake array films resulted in higher photoelectrochemical ⁴⁰ activity compared to the un-doped BiVO₄ films.

2. Experimental

2.1 Material Synthesis

Bi(NO₃)₃·xH₂O (Alfa Aesar, 99.999%), VCl₃ (Sigma-Aldrich, 45 97%), (NH₄)₆Mo₇O₂₄·4H₂O (Sigma-Aldrich, 99.98%) and (NH₄)₁₀W₁₂O₄₁·5H₂O (Sigma-Aldrich, 99.99%) were dissolved separately at a concentration of 75 mM in ethylene glycol (Fischer, 99+%) as metal precursor solutions. 0.85 g polyethylene glycol 600 (PEG-600, Alfa Aesar) was dissolved in 25 mL 50 ethylene glycol to create the structure directing agent solution. The precursor solutions were mixed in the desired Bi: V: W: Mo atomic ratios with PEG-600 solution. Based on the best doping levels from previous work,²² the Bi: V: W: Mo atomic ratios of the films are as follows: 50: 50: 0: 0 for BiVO₄, 48.75: 48.75: 2.5: 55 0 for 2.5%W doped BiVO₄, 47.5: 47.5: 0: 5 for 5%Mo doped BiVO₄ and 46: 46: 2: 6 for 2%W, 6% Mo co-doped BiVO₄. The typical experimental procedure for synthesizing BiVO₄ nanoflake array films in as follows: 500 µL Bi(NO₃)₃ solution, 500 µL VCl₃ solution and 250 µL PEG-600 solution were mixed to form a 60 precursor solution that is green color. Next, 200 µL of precursor solution was drop-cast on FTO coated glass substrates (1.5×1.5 cm, Pilkington, TEC15) that had been cleaned and sonicated with enthanol (Fischer, 99+%). The sample was dried in an oven at 135 °C for 55 min and then annealed in air at 500 °C for 2.5

hours, a yellow/orange film was obtained on the FTO substrates. For comparison, different morphologies of BiVO₄ films were synthesized via adjusting the synthesis conditions, such as the concentration of PEG-600, and drying time for the precursor 5 solution. All films had the same mass of active material, so that the effects of morphology could be observed.

2.2 Material Characterization

Scanning electron microscopy (SEM) images were acquired using a Zeiss Supra 40 VP SEM. X-ray diffraction (XRD) ¹⁰ measurements were taken on a Rigaku Spider X-ray diffractometer using powder samples. X-ray photoelectron spectroscopy (XPS) measurements were performed on a Kratos AXIS Ultra DLD system with monochromated Al-Kα radiation. UV-vis transmission measurements were performed with a Cary ¹⁵ 5000 UV-vis spectrometer. For Tauc plots the absorption coefficient (α) was determined by:

$$\alpha = -\ln (10^{-\text{absorbance}})/z \qquad (1)$$

where z is the film thickness.

2.3 Electrochemical and Photoelectrochemical Measurements

The electrochemical and photoelectrochemical measurements were conducted using a three-electrode cell, which had a main compartment for the working electrode and two branched compartments separated by fritted disks (Ace Glass, 10-20 μm porosity) for the counter electrode and reference electrode. The ²⁵ working electrode was the as synthesized film which was pressed against an O-ring on the main compartment. It had a backside mask so that the active area was approximately 0.22 cm² for both frontside and backside illumination measurements. The counter electrode was a 1 mm diameter Pt wire (99.95%, Alfa Aesar) and ³⁰ the reference electrode was Ag/AgCl (sat. KCl, CH Instruments, CH111). Each compartment of the cell was filled from the same stock of electrolyte solution. The pH of the solution was checked

using a bench top pH meter (OAKTON). A CH Instruments 660D electrochemical workstation was employed for the ³⁵ electrochemical measurements.

The illumination source was a 150 W xenon lamp (Newport, Model 9600) with an AM 1.5G filter (Newport). For light measurements the lamp was positioned to provide approximately 100 mW/cm² irradiation on the film as measured by a thermopile 40 detector (Newport, Models 1916C and 818-UV). In the present work, the photoelectrochemical measurements for the films are conducted using back-side illumination (through the FTO-glass substrate to film). IPCE measurements were conducted using a full solar simulator (Newport, Model 9600, 150 W xenon lamp) 45 with an AM 1.5 filter and a motorized monochromator (Oriel Cornerstone 130 1/8 m). The monochromator slit size was adjusted to 0.75 mm × 2 mm providing monochromatic wavelengths and a power density which could be adjusted from 12.8 and 252.3 μ W/cm² of irradiation for wavelengths between 50 340 and 520 nm. A typical light power density used for the IPCE measurements can be found in Fig. S8. Light power was measured using a handheld optical power meter with a UV enhanced silicon photo-detector (Newport, Models 1916C and 818-UV). The IPCE is expressed by following equation:

IPCE=
$$(1240 \times I)/(\lambda \times P_{light})$$

(2)

where I is the measured photocurrent density at a specific wavelength (mA cm⁻²), λ is the wavelength of incident light (nm) and P_{light} is the measured light power density at that wavelength (mW cm⁻²).

⁶⁰ The electrochemical impedance spectroscopy (EIS) was performed using a CH Instruments 660D in 0.2 M Na₂SO₄ solution and 0.1 M phosphate buffer solution (pH 6.6). The Nyquist plots were measured at 0.8 V (*vs.* Ag/AgCl) with an AC amplitude of 5 mV, frequency of 100 kHz-100 mHz under AM ⁶⁵ 1.5 G illumination (100 mW/cm²). The measured spectra were

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fitted by using the Zview software. For converting the potential *vs.* Ag/AgCl to RHE the following equation was used:

$$E_{RHE} = E_{Ag/AgCl} + 0.059 \, pH + 0.197 \, V \quad (3)$$

Mott-Schottky measurements were conducted using a CH 5 Instruments 660D and the built in software was used to measure capacitance *vs.* applied potential at a fixed frequency. Mott-Schottky plots were created and fit to ideal semiconductor behavior:

$$1/C^2 = (2/e\varepsilon\varepsilon_0 N_d)[V_a - V_{fb} - kT/e]$$
(4)

¹⁰ here *C* is the space charge layer capacitance, ε is the dielectric constant of the material, ε_0 is the permittivity of vacuum, *e* is the elemental charge, N_d is the concentration of charge carriers, V_a is the applied potential, V_{fb} is the flat band potential, *k* is Boltzmann's constant, and *T* is temperature.

15 3. Results and Discussion

Generally, the photoelectrochemical activity of BiVO₄ is dependent on their morphology, while the BiVO₄ morphology is strongly dependent on the synthesis condition and method. To optimize the photoelectrochemical activity, BiVO₄ films with ²⁰ different morphologies were synthesized on FTO substrates using a drop-casting method. The synthesis conditions and the corresponding products are summarized in Table 1.

Table 1 Summary of synthesis conditions versus the BiVO4products.

Sample no.	Bi:V:PEG-600 (volume ratio)	Precursor solution drying time (min)	Relevant Figure Number	
la	2:2:0	55	Fig. 1a and Fig. S1a	
1b	2:2:1	55	Fig. 1b, 1c, Fig. S1b and Fig. 2b	
1d	2:2:2	55	Fig. 1d and Fig. S1c	
2a	2:2:1	0	Fig. 2a	
2c	2:2:1	110	Fig. 2c	



Fig. 1 SEM images of $BiVO_4$ films on FTO substrate synthesized ³⁰ from a precursor solution containing Bi^{3+} , V^{3+} and PEG-600 with Bi: V: PEG-600 (volume ratio) = (a) 2:2:0, (b) and (c) 2:2:1, (d) 2:2:2.

Fig. 1 shows SEM images for the BiVO₄ films synthesized from a precursor solution containing equal molar Bi3+ and V3+ with different amounts of polyethylene glycol 600 (PEG-600). As shown in Fig. 1a, non-uniform flake-like BiVO4 are obtained 5 from the PEG-600-free precursor solution. In addition, the edge of the film is cracked and the coverage is not uniform because of precursor solution bubbling during the annealing process (see Fig. S1a in the Supporting Information). Adding PEG-600 into the precursor solution (Bi: V: PEG-600=2:2:1, volume ratio) results ¹⁰ in uniform BiVO₄ films on the FTO substrate (Fig. S1b). The topview and cross-sectional images in Fig. 1b and 1c revealed that the BiVO₄ film is composed of flakes with an average thickness of 20 nm and length of 2 µm. Interestingly, the morphology of the BiVO₄ film completely changed when more PEG-600 was added 15 into the precursor solution. As shown in Fig. 1d, the BiVO₄ film synthesized from a higher-concentration PEG-600 precursor solution (Bi: V: PEG-600=2:2:2) consists of agglomerated BiVO₄ nanoparticles. Additionally, the coverage, especially near the edge of the film is worse (see Fig. S1c), which is similar to 20 BiVO₄ films synthesized from the PEG-600-free precursor solution. From these results, it is clear that the macroscopic homogeneity of the BiVO₄ film as well as the morphology is controllable by adding PEG-600 into the precursor solution. Polyethylene glycol (PEG) is commonly used as a morphology-25 directing agent for synthesizing nanostructured materials, usually acting by confining the crystal growth in certain directions.³³⁻³⁵ It has been reported that PEG can play a role as the morphologydirecting agent in synthesis of some metal oxides such as ZnO and Fe_3O_4 nanowires, mesoporous WO₃ and WO₃ nanoflakes.³⁰⁻ 30^{32, 36} In the present work, to confirm the effect of PEG-600, we added polyethylene glycol 300 (PEG-300) into the precursor solution as a morphology-directing agent for synthesizing

nanostructured BiVO₄, it was found that the BiVO₄ film synthesized from this precursor solution did not adhere well to ³⁵ the FTO substrate and the film consisted of highly non-uniform BiVO₄ (see Fig. S2, Supporting Information). The crystal structure of the films synthesized with varying PEG-600 content was determined by X-ray diffraction (XRD) and the patterns are shown in Fig. S3 of the Supporting Information. All of the as-⁴⁰ synthesized films could be indexed to monoclinic BiVO₄ (JCPDS No. 01-075-1867).



⁴⁵ Fig. 2 SEM images of BiVO₄ films on FTO substrate synthesized from a precursor solution containing Bi³⁺, V³⁺ and PEG-600 (Bi: V: PEG-600=2:2:1) with (a) 0 min, (b) 55 min and (c) 110 min drying time for the precursor solution at 135 °C.

The dependence of the BiVO₄ nanostructures on the precursor solution drying time is shown in Fig. 2. Fig. 2a shows a SEM image of the BiVO₄ film synthesized from the drop-casting method without a precursor solution drying process, i.e., the 5 precursor solution was drop-cast on the FTO substrates, and then directly annealed at 500 °C for 2.5 hours. As shown in Fig. 2a, a flake array of BiVO₄ was formed, but the thickness of the flakes was not highly uniform. This may be attributed to the quick evaporation of precursor solution during the high temperature ¹⁰ annealing process resulting in uneven growth of BiVO₄ crystals. We added an intermediate drying step for the precursor solution at 135 °C for 55 min to form a uniform colloid film and then annealed it at 500 °C for 2.5 hours. As shown in Fig. 2b, BiVO₄ nanoflake arrays were obtained after this drying step was 15 included. Nevertheless, the colloidal BiVO₄ appears to agglomerate during a longer drying time (110 min), leading to larger, thicker BiVO₄ flakes (see Fig. 2c).

The photoelectrochemical activity of nanostructured BiVO₄ films (shown in Fig. 1a, Fig. 1b, Fig. 2a and Fig. 2c) was ²⁰ investigated by linear sweep voltammetry (LSV). The LSV measurements were conducted in 0.2 M Na₂SO₄ and 0.1M phosphate buffer solution (pH 6.6) illuminated with 100 mW/cm² simulated solar light. The LSV results indicated that the BiVO₄ film (shown in Fig. 1b and 2b) synthesized from the precursor ²⁵ solution with a Bi: V: PEG-600 volume ratio of 2:2:1 and dried at 135°C for 55 min has the best photoelectrochemical activity (see Fig. S4, Support Information). Thus, this precursor solution and drying condition was used to synthesize the un-doped and doped BiVO₄ films for subsequent experiments.

³⁰ Based on previous studies, it was found that Mo and W doped BiVO₄ films have better photoelectrochemical activity than undoped BiVO₄ films for water oxidation, especially 2.5% W doped, 5% Mo doped and 2% W, 6% Mo co-doped BiVO₄ films.^{21,22} Herein we synthesized the corresponding doped BiVO₄ ³⁵ films by adding appropriate amounts of W and Mo into the BiVO₄ precursor solutions. As shown in Fig. 3, the doped BiVO₄ films exhibit similar morphology compared to the un-doped BiVO₄ films, although some small differences from the un-doped films due to the co-incorporation of W and Mo are visible. XRD ⁴⁰ performed on these films (Fig. 4) showed no tungsten or molybdenum oxide formation, implying the different morphology flakes are still single phase BiVO₄ flakes, but slight changes in crystal structure closer to tetragonal with Mo and/or W incorporation.



Fig. 3 SEM images of (a) 2.5% W doped BiVO₄ film, (b) 5% Mo doped BiVO₄ film and (c) 2%W, 6% Mo co-doped BiVO₄ film.



Fig.4 (a) XRD patterns of BiVO₄, 2.5% W doped BiVO₄, 5% Mo s doped BiVO₄, 2%W, 6% Mo co-doped BiVO₄. The boxes highlight the peaks that shift with W and Mo doping. High resolution XPS spectrum of (b) Bi 4f, (c) O 1s and V 2p, (d) Mo 3d and (e) W 4f.

Table 2 XPS data for BiVO₄ and doped BiVO₄ films

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	Sample	XPS measured atomic ratio (Bi : V : W : Mo)	Designed atomic ratio (Bi : V : W : Mo)
	BiVO ₄	52:48:0:0	50:50:0:0
	2.5% W-BiVO ₄	49:48:3:0	48.75 : 48.75 : 2.5 : 0
	5% Mo-BiVO ₄	50:44:0:6	47.5: 47.5: 0: 5
	2% W, 6%Mo- BiVO ₄	51:42:2:5	46:46:2:6

The XRD measurements were conducted using powder samples that were scraped from the films. In the pure $BiVO_4$

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pattern, all of the characteristic diffraction peaks are in good agreement with the standard data for monoclinic BiVO₄ (JCPDS 15 No. 01-075-1867). For the doped samples, only peaks for monoclinic BiVO₄ were observed. However, as highlighted in Fig. 4a, three pairs of BiVO₄ peaks tended to merge into three single peaks after doping. For example, the (200) BiVO₄ peak at 34.5° and (002) peak at 35.2° shifted toward each other after 2.5% W ²⁰ doped into BiVO₄, and the two peaks merged into a single peak at 34.9° for 5% Mo doped and 2%W, 6% Mo co-doped BiVO₄ samples. This behavior was also observed for the (240) and (042) peaks at 46.7° and 47.9° and the (321) and (123) peaks at 58.3° and 59.4°. Similar observations were reported in previous work 25 related to Mo and W doped BiVO₄.^{21, 22} The merging of peaks can be attributed to a change in the crystal structure from monoclinic to tetragonal symmetry.37 The surface composition of the films was verified by X-ray photoelectron spectroscopy (XPS) measurements. The high resolution XPS spectra of the Bi 4f, O 1s, 30 V 2p, Mo 3d and W 4f binding energy regions for a representative 2%W, 6% Mo co-doped BiVO₄ sample are shown from Fig. 4b to 4e. The characteristic orbital splitting of the Bi $4f_{5/2}$ and Bi $4f_{7/2}$ peaks (Fig. 4b), and the V $2p_{1/2}$ and V $2p_{3/2}$ peaks (Fig. 4c) were observed with peak locations of 164.4, 159.1, 35 524.4 and 516.9 eV, respectively, closely matching the Bi³⁺ and V⁵⁺ peaks in monoclinic scheelite BiVO₄.^{22, 38} For the O 1s peak, an additional small peak was seen which can be attributed to hydroxyls binding at defect sites.^{22, 39} The Mo $3d_{3/2}$ and Mo $3d_{5/2}$ peaks were located at 235.4 and 232.2 eV (Fig. 4d), and the W 4f $_{40}$ _{5/2} and 4f _{7/2} peaks were observed at 37.3 and 35.2 eV (Fig. 4e), confirming the presence of Mo⁶⁺ and W⁶⁺ species in BiVO₄.^{40, 41} Using the XPS spectra, the Bi: V: W: Mo atomic ratios of the films were measured and are summarized in Table 2.

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Fig.5 Average chopped LSV scans for the BiVO₄ nanoparticle film, BiVO₄ nanoflake array film, 2.5% W doped BiVO₄ film, 5% 5 Mo doped BiVO₄ film and 2% W, 6% Mo co-doped BiVO₄ film in (a) 0.2 M Na₂SO₄ and 0.1 M phosphate buffer solution (pH 6.6) and (b) 0.2 M Na₂SO₃ and 0.1 M phosphate buffer solution (pH 6.9) under illumination with 100 mW/cm² light. The scan rate was 25 mV/s.

- Fig. 5a shows the average chopped LSV collected from the BiVO₄ nanoparticle films (the film shown in Fig. 1d), BiVO₄ nanoflake array films (shown in Fig. 1b and 2b), 2.5% W doped BiVO₄ films (shown in Fig. 3a), 5% Mo doped BiVO₄ films (shown in Fig. 3b) and 2% W, 6% Mo co-doped BiVO₄ films 15 (shown in Fig. 3c) in 0.2 M Na₂SO₄ and 0.1 M phosphate buffer
- solution (pH 6.6) illuminated with 100 mW/cm² light. The original LSV's measured on 12 films are shown in Fig. S5 of the supporting information. As shown in Fig. 5a, the lowest photocurrent was generated by the $BiVO_4$ nanoparticle film. In

20 contrast, the BiVO₄ nanoflake array film showed a more pronounced photoresponse, indicating that the nanoflake structure is advantageous for achieving higher photoelectrochemical activity. For example, at 1.0 V vs. Ag/AgCl, the photocurrent density for the nanoflake array film was 0.68 mA/cm² and 0.23 25 mA/cm² for the nanoparticle film. The higher activity of the BiVO4 nanoflake array film is due to a larger film/electrolyte interfacial area and reduction of the necessary holes transport length compared to the nanoparticle film. After doping with W and Mo, the nanostructured BiVO4 films show further enhanced 30 activity. With respect to the photocurrent density for the doped BiVO₄ films, there is little difference between the 5% Mo-BiVO₄ film (1.29 mA/cm² at 1.0 V vs. Ag/AgCl) and the 2% W, 6% Mo co-doped BiVO₄ film (1.28 mA/cm² at 1.0 V vs. Ag/AgCl), but both are higher than that for the 2.5% W-BiVO₄ film (0.91 ³⁵ mA/cm² at 1.0 V vs. Ag/AgCl). For further comparison, we tested the films in 0.1 M phosphate buffer (pH 6.9) with 0.2 M Na₂SO₃ added as a hole scavenger. In general, the results (see Fig. 5b) are consistent with the chopped LSV results measured in the buffered 0.2 M Na₂SO₄. Namely, the photoelectrochemical activity of the 40 BiVO₄ nanoflake array film was better than that of the nanoparticle film and the doped BiVO₄ films' activity was higher than the un-doped BiVO₄ films. It is noteworthy that the 2% W, 6% Mo co-doped $BiVO_4$ film shows the highest photocurrent out of all the films tested in Na₂SO₃ solution. In summary, the 45 photoelectrochemical activity of the films can be ranked in the following order: BiVO₄ nanoparticle film < BiVO₄ nanoflake array film < 2.5% W-BiVO₄ nanoflake array film < 5% Mo- $BiVO_4$ nanoflake array film < 2%W, 6% Mo- $BiVO_4$ nanoflake array film. The present results are similar to our previous study 50 and a scanning electrochemical microscopy study of BiVO4 doping that found W, Mo co-doped BiVO4 resulted in higher photoelectrochemical activity for water oxidation than individual Mo and W doped BiVO₄ and un-doped BiVO₄.^{21, 22} DFT calculations suggest that W and Mo can act as effective shallow donors to increase the total carrier density, which could result in s enhanced photoelectrochemical activity.^{21, 23, 42} On the other hand, experimental data from Abdi *et al* showed that W doping of BiVO₄ decreases the carrier mobility by introducing mid-bandgap defects which act as carrier traps.²⁰ DFT calculations show that W and Mo doping into BiVO₄ may produce excellent *n*-type 10 conductivity.⁴² And Hoffart et al. showed that 5% Mo doped BiVO₄ had a total conductivity at least an order of magnitude higher than BiVO₄ at 600°C.⁴³ Thus, the improved conductivity in doped BiVO₄ may enhance its photoelectrochemical activity.

In order to understand the origin of the photoelectrochemical 15 activity enhancement in the doped film, we investigated the optical behavior of the films using UV-vis absorbance spectroscopy (see Fig. S6a). Regardless of the amount of W and Mo incorporation, all of the films had a band gap of approximately 2.4 eV (Fig. S6b) and similar absorbed photon 20 flux, indicating this cannot be the sole cause of the increased photoactivity (Fig. S6c). In addition, the water oxidation kinetics at the interface of the photoanode/electrolyte were evaluated by electrochemical impedance spectroscopy (EIS).23, 28, 44 The EIS spectra are presented as Nyquist plots in Fig. 6a. The EIS 25 measurements were performed in 0.2 M Na₂SO₄ and 0.1 M phosphate buffer solution (pH 6.6) under simulated solar light illumination (100 mW/cm²). The Nyquist plots were interpreted in terms of the equivalent circuit shown in the inset of Fig. 6a. In the plot, the symbols indicate the experimental results and the 30 lines represent fitting results. In the equivalent circuit, Rs is the solution resistance, CPE is the constant phase element for the electrolyte/electrode interface, and Rct is the charge transfer

resistance across the electrode/electrolyte interface. The arcs in the Nyquist plot are related to charge transfer at the interface of ³⁵ the electrode/electrolyte. As shown in Fig. 6a, under illumination both Nyquist diagrams display a typical semicircle arc in the measured frequency region, and the semicircle arc for the 2% W, 6% Mo co-doped BiVO₄ film was smaller than that for the BiVO₄ film, indicating faster water oxidation kinetics. As shown in ⁴⁰ Table 3, the Rct value for the BiVO₄ film was 3216 Ω and for the 2% W, 6% Mo co-doped BiVO₄ film the value was 2931 Ω . Therefore, the enhanced photoelectrochemical activity for the 2% W, 6% Mo co-doped BiVO₄ film may be ascribed to the enhanced water oxidation kinetics.

The flat band potentials of the BiVO₄ nanoflake array film and the 2% W, 6% Mo co-doped BiVO4 film were also measured in 0.2 M Na₂SO₄ and 0.1 M phosphate buffer solution (pH 6.6). Fig. 6b and 6c present the Mott–Schottky plots $(1/C^2 vs. V)$ measured at different frequencies. The Mott-Schottky plots for the BiVO₄ 50 and the co-doped BiVO4 film both showed quasi-linear behavior. The plots indicate that the flat band potentials of the BiVO₄ film and 2% W, 6% Mo co-doped BiVO4 film were around -0.45 V and -0.35 V (vs. Ag/AgCl), respectively. Although the measured flat band potentials have certain deviations due to 55 nanostructuring,⁴⁵ since the deviations should be similar for both films, it seems that that the flat band position of the co-doped BiVO₄ film shows a positive shift of about 100 mV compared with the un-doped BiVO₄ film. This is consistent with previous work related to W and Mo doped BiVO₄ showing a positive shift 60 of the flat band potential.²¹⁻²³

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Fig. 6 (a) Electrochemical impedance spectra of the BiVO₄ and
2% W, 6% Mo co-doped BiVO₄ film under simulated solar illumination (100 mW/cm²). The solid line was fitted by Zview software using the proposed equivalent circuit model. The EIS was measured at 0.8 V (vs. Ag/AgCl) in 0.2 M Na₂SO₄ solution and 0.1 M phosphate buffer solution (pH 6.6). The inset ¹⁰ shows an equivalent circuit for the photoanodes. Mott–Schottky plots for (b) the BiVO₄ nanoflake array film and (c) 2% W, 6% Mo co-doped BiVO₄ nanoflake array film. The measurements were conducted in 0.2 M Na₂SO₄ solution and 0.1 M phosphate buffer solution (pH 6.6).

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Table 3 The values of the elements in equivalent circuit fitted inthe Nyquist plots of Fig. 6a.

Sample	Rs (Ω)	CPE1-T(F) /	CPE1-P/	$\operatorname{Rct}(\Omega)$ /
	/Error(%)	Error(%)	Error(%)	Error(%)
BiVO ₄	116.2/1.16	9.56E-6/5.04	0.782/0.92	3216/3.23
2% W, 6% Mo-BiVO ₄	114.4/1.25	2.61E-5/5.02	0.684/1.08	2931/3.84



Fig. 7 Amperometric i-t curve for the BiVO₄ nanoparticle film, BiVO₄ nanoflake array film, 2.5% W doped BiVO₄ film, 5% Mo doped BiVO₄ film and 2% W, 6% Mo co-doped BiVO₄ film under ²⁵ illumination with 100 mW/cm² light in (a) 0.2 M Na₂SO₄ and 0.1 M phosphate buffer solution (pH 6.6) at a constant applied potential of 1.0 V vs.Ag/AgCl (1.59 V vs RHE) and (b) 0.2 M Na₂SO₃ and 0.1 M phosphate buffer solution (pH 6.9) at a constant applied potential of 0.5 V vs.Ag/AgCl (1.1 V vs RHE).

The stability of the films was investigated by chronoamperometry. We first conducted stability testing in 0.2 M Na₂SO₄ solution and 0.1 M phosphate buffer solution (pH 6.6) at a constant applied potential of 1.0 V vs. Ag/AgCl. As shown in Fig. 7a, the photocurrent on all of the films decreased after 3600 35 seconds of testing under illumination in Na₂SO₄ solution, which was mainly ascribed to material photocorrosion and vanadium dissolution.^{15, 46} XPS analysis of the BiVO₄ film reveals that the atomic ratio of Bi/V decreased from 52/48 to 55/45 after the stability testing, indicating a loss of vanadium at the surface. 40 Furthermore, the SEM images acquired from the BiVO₄ film shows that the BiVO₄ nanoflakes were damaged after 3600 seconds of illumination during stability testing (see Fig.S7 in

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Supporting Information). However, the photoelectrochemical activity of the films tend to stabilize after the rapid initial decrease in photocurrent in 0.2 M Na₂SO₃ solution and 0.1 M phosphate buffer solution (pH 6.9) (see Fig. 7b) because of the ⁵ protection provided by SO³⁻ against the photocorrosion. This indicates that the corrosion mainly occurs at the surface and the holes may be quickly injected into the SO³⁻ before having a chance to promote a reaction within the BiVO₄. Generally, the i-t testing results are consisitant with the chopped LSV results in Na₂SO₃ solution. On the other hand, the 2% W, 6% Mo co-doped BiVO₄ film showed the highest photocurrent retention both in Na₂SO₄ and Na₂SO₃ solution, this point is a little different from the chopped LSV result measured in Na₂SO₄ where 5% Mo doped films have the highest photocurrent.



Fig. 8 IPCE spectra for the BiVO₄ nanoparticle film, BiVO₄ nanoflake array film, 2.5% W doped BiVO₄ film, 5% Mo doped BiVO₄ film and 2% W, 6% Mo co-doped BiVO₄ film in (a) 0.2 M
²⁰ Na₂SO₄ and 0.1 M phosphate buffer solution (pH 6.6) at a constant applied potential of 1.0 V vs.Ag/AgCl (1.59 V vs RHE) and (b) 0.2 M Na₂SO₃ and 0.1 M phosphate buffer solution (pH

6.9) at a constant applied potential of 0.5 V vs.Ag/AgCl (1.1 V vs RHE).

The relationship between the photoelectrochemical activity and the wavelength of the incident light was investigated by incident photon-to-current conversion efficiency (IPCE). Fig. 8 shows the IPCE spectra for the films measured in 0.2 M Na₂SO₄ buffered solution at 1.0 V vs.Ag/AgCl and 0.2 M Na₂SO₃ buffered 30 solution at 0.5 V (vs.Ag/AgCl), the spectra are integrated and compared to the LSV results in Tables S1 and S2. For all of the films, the photoresponse was observed from 340 to 520 nm, which is in agreement with their UV-vis absorbance spectra. Additionally, in comparison to the BiVO₄ films, the doped BiVO₄ 35 films exhibit enhanced IPCE over the entire absorption region and the 2% W, 6% Mo co-doped BiVO4 film presents the highest IPCE. The IPCE results further confirmed W and Mo co-doping photons for BiVO₄ enhances the harvesting of of photoelectrochemical reactions.

40 4. Conclusions

In summary, a simple drop-casting method was developed to synthesize un-doped and doped BiVO₄ nanoflake array films on FTO coated glass substrates. The influence of synthesis parameters including the amount of polyethylene glycol 600 ⁴⁵ (PEG-600) and the precursor solution drying time on the growth of BiVO₄ film were investigated to optimize the films for photoelectrochemical water oxidation. The BiVO₄ films synthesized from a precursor solution containing Bi³⁺, V³⁺ and PEG-600 with a Bi: V: PEG-600 volume ratio of 2: 2: 1 dried at ⁵⁰ 135°C for 55 min were composed of nanoflake arrays with an average thickness of 20 nm and length of 2 μm. The electrochemical results show that the BiVO₄ nanoflake array films have higher photoelectrochemical activity than the BiVO₄ nanoparticle films. Additionally, further enhanced photoelectrochemical activity was observed on the 2% W and 6% Mo co-doped BiVO₄ film. We believe that this facile drop-casting method may be suitable for synthesizing nanostructured BiVO₄- ⁵ based materials for use in solar energy devices.

Notes

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† Electronic Supplementary Information (ESI) available:
Photographs of BiVO₄ films, XRD patterns of BiVO₄, SEM
²⁰ images of BiVO₄, LSV scans for nanostructured BiVO₄ films, UV-vis absorbance spectra and Tauc plots of the films, the incident light power density spectrum used for the IPCE measurements and the integral photocurrent values for the films using the IPCE data. See DOI: 10.1039/b000000x/

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